

Measurement of impurity ion temperature using charge exchange recombination spectroscopy in Heliotron J

ヘリオトロンJにおける荷電交換再結合分光による
不純物イオン温度分布計測

Takayuki Minami¹, Shinji Kobayashi², Hyunyong Lee¹, Shinichiro Kado³, Tohru Mizuuchi², Kazunobu Nagasaki², Hiroyuki Okada², Takashi Minami², Satoshi Yamamoto², Shinsuke Ohshima⁵, Tomotaka Harada⁶, Tasuku Kagawa¹, Kiyofumi Mukai¹, Linge Zang¹, Shohei Arai¹, Hiroaki Yashiro¹, Hiroto Watada¹, Yoshinobu Wada¹, Sadayoshi Murakami⁴, Yuji Nakamura¹, Kiyoshi Hanatani², Shigeru Konoshima², Fumimichi Sano²

南 貴之¹, 小林進二², H.Y. Lee¹, 門信一郎³, 水内 亨², 長崎百伸², 岡田浩之², 南 貴司², 山本 聡², 大島慎介⁵, 原田伴誉⁶, 香川 輔¹, 向井清史¹, L. Zang¹, 荒井翔平¹, 八代浩彰¹, 和多田泰士¹, 和田善信¹, 村上定義⁴, 中村祐司¹, 花谷 清², 木島 滋², 佐野史道²

¹Graduate School of Energy Science, Kyoto University, Gokasho, Uji, 611-0011, Japan

京都大学大学院エネルギー科学研究科 〒611-0011 京都府宇治市五ヶ庄

²Institute of Advanced Energy, Kyoto University, Gokasho, Uji, 611-0011, Japan

京都大学エネルギー理工学研究所 〒611-0011 京都府宇治市五ヶ庄

³Graduate School of Engineering, University of Tokyo, 7-3-1 Hongo, Bunkyo-ku, 113-8656, Japan

東京大学大学院工学系研究科 〒113-8656 東京都文京区本郷 7-3-1

⁴Graduate School of Engineering, Kyoto University, Yoshidahontyo, Sakyo-ku, 606-8501, Japan

京都大学大学院工学研究科 〒606-8501 京都府京都市左京区吉田本町

⁵Pioneering Research Unit for Next Generation, Kyoto University, Gokasho, Uji, 611-0011, Japan

京都大学次世代開拓ユニット 〒611-0011 京都府宇治市五ヶ庄

⁶Undergraduate School of Electrical and Electronic, Faculty of Engineering, Kyoto University, Yoshidahonmachi, Sakyo-ku, 606-8501, Japan

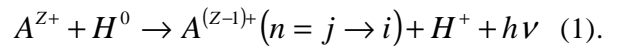
京都大学工学部電気電子工学科 〒606-8501 京都府京都市左京区吉田本町

This paper describes the measurement of the impurity ion temperature using Charge eXchange Recombination Spectroscopy (CXRS) in Heliotron J. The measurable range of the CXRS system has been extended from $0.37 < \rho < 0.79$ to $0.07 < \rho < 0.94$ with the spatial resolution $\Delta\rho \sim \pm 0.05$ by installing newly designed sightlines. The radial profile of the carbon ion temperature was measured in NBI plasmas. The core ion temperature with CXRS is consistent with that measured with a charge exchange neutral particle analyzer.

1. Introduction

In magnetically confined plasmas, the measurement of the radial profile of the plasma pressure and the rotation velocities (v_t and v_p) is indispensable not only for the heat or particle transport analysis but also for the evaluation of the radial electric field. The Charge eXchange Recombination Spectroscopy (CXRS) has been utilized for the measurements of the radial profile of the impurity ion temperature, density and rotation velocity in high temperature fusion plasmas [1]. The ion temperature and the rotation velocity are evaluated from the Doppler broadening and the Doppler shift of the line emission from the Charge eXchange Recombination (CXR) reaction between the fully

ionized impurity ions (A^{Z+}) and the neutral beam particles (H^0) as follows:



In Heliotron J, a CXRS system has been developed, and the ion temperature has been measured in the range of $0.37 < \rho < 0.79$ [2], where ρ is the normalized minor radius. We have recently introduced a new objective optical system in order to extend the measurable area. We show initial results of the radial profile measurements of the impurity ion temperature.

2. CXRS system in Heliotron J

Figure 1 shows a schematic of the CXRS system

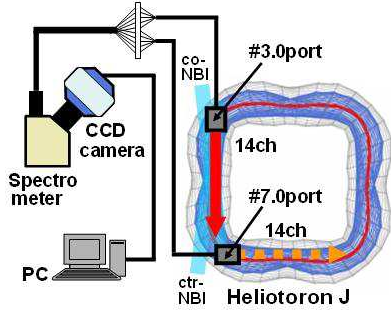


Fig.1. Schematic of CXRS system in Heliotron J

in Heliotron J, a helical-axis heliotron device with an $L=1/m=4$ helical coil. Two sets of NBI (co and ctr) for plasma heating are used as diagnostic beams. An emission line of CVI ($n=8 \rightarrow 7$, 529.05 nm) is used for the CXRS measurement since no strong line spectrum is observed near this wavelength and we can use fiber bundles to guide the emission to a spectrometer. Two sets of the 14 sightlines are newly installed for the beam-carbon CXR emission (#3.0 port) and the background emission (#7.0 port). To optimize the spatial resolution of the CXR measurement, the sightlines are chosen in parallel to the magnetic axis by taking into account the region of the neutral beam passing. Figure 2 shows the radial positions of the sightlines as a function of the distance from the pivot point for this system. This optimization enables us to measure the radial profile of the CXR emission in the range of $0.07 < \rho < 0.94$ with the spatial resolution of $\Delta\rho \sim \pm 0.05$.

The plasma emission is led to a Czerny-Turner monochromator whose focus length is 400 mm, F number is 2.8 and grating is 2160 grooves/mm. A CCD camera (ANDOR DU-897, 512×512 pixels and $16 \times 16 \mu\text{m}$) was installed to detect the spectral and spatial profile of the CXR emission.

3. Experiments

Figure 3 shows an example of the radial profile of the carbon ion temperature and its time evolution. The plasma was generated by ECH, and sustained

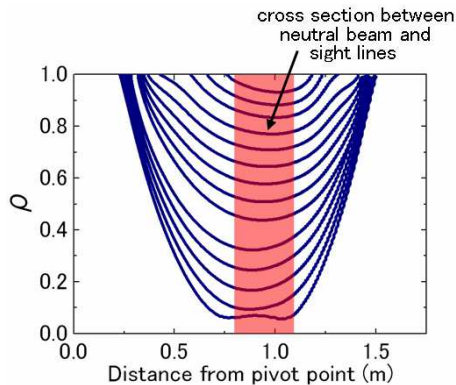


Fig.2. Radial positions of channels

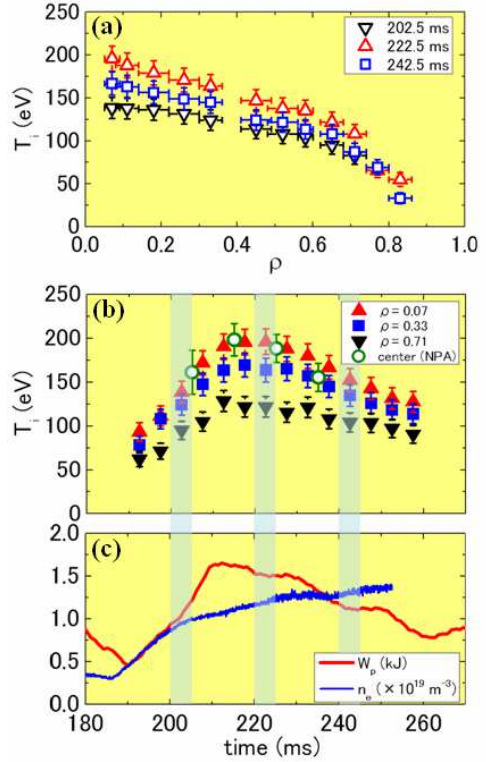


Fig.3. (a) radial profile of T_i , (b) time evolution of T_i at three radial positions, (c) the stored energy W_p and the line-averaged electron density

only by NBI from 170 ms to 270 ms. The NBI port-through power was 920 kW in total. As shown in Fig. 3(a), we obtained the ion temperature profile in the range of $0.07 < \rho < 0.83$. In the peripheral region $\rho > 0.83$, however, the intensity of the CXR emission was too low to estimate the ion temperature. The radial profile has a peaked shape, and the temperature reached up to 200 eV at $\rho=0.07$. Figure 3(b) shows the time evolution of the carbon ion temperature at three radial positions. The bulk (deuterium) ion temperature measured with a Charge eXchange Neutral Particle Analyzer (CX-NPA) is also plotted in the figure. The center carbon ion temperature agrees well with the bulk ion temperature.

4. Summary

We measured the radial profile and time evolution of the carbon ion temperature using the CXRS in Heliotron J. The radial profile measured in the range of $0.07 < \rho < 0.83$ has a peaked shape. The ion temperature reaches up to 200 eV at the core, and its time evolution agrees well with the bulk ion temperature measured with the CX-NPA.

References

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